

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination TERASHIMA ET AL.	
		Examiner John P. Sheehan	Art Unit 1793	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0116236 A1	06-2003	Hayakawa et al.	148/516
*	B	US-2001/0030001	10-2001	Hayakawa et al.	148/111
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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